## Features

- Qualified for Automotive Applications
- Wide Range of Digital and Analog Signal Levels
- Digital: 3 V to 20 V
- Analog: $\leq 20 \mathrm{~V}_{\mathrm{P}-\mathrm{P}}$
- Low ON Resistance, $125 \Omega$ (Typ) Over $15 \mathrm{~V}_{\text {P-p }}$ Signal Input Range for $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}=18 \mathrm{~V}$
- High OFF Resistance, Channel Leakage of $\pm 100 \mathrm{pA}$ (Typ) at $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}=18 \mathrm{~V}$
- Logic-Level Conversion for Digital Addressing Signals of 3 V to 20 V ( $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}}=3 \mathrm{~V}$ to 20 V ) to Switch Analog Signals to $20 \mathrm{~V}_{\mathrm{P}-\mathrm{P}}\left(\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}=20 \mathrm{~V}\right)$
- Matched Switching Characteristics, $r_{o n}=5 \Omega$ (Typ) for $V_{D D}-V_{E E}=15 \mathrm{~V}$
- Very Low Quiescent Power Dissipation Under All Digital-Control Input and Supply Conditions, $0.2 \mu \mathrm{~W}$ (Typ)
at $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}}=\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}=10 \mathrm{~V}$
- Binary Address Decoding on Chip
- 5-V, 10-V, and 15-V Parametric Ratings
- 100\% Tested for Quiescent Current at 20 V
- Maximum Input Current of $1 \mu \mathrm{~A}$ at 18 V Over Full Package Temperature Range, 100 nA at 18 V and $25^{\circ} \mathrm{C}$
- Break-Before-Make Switching Eliminates Channel Overlap


## Applications

- Analog and Digital Multiplexing and Demultiplexing
- Analog-to-Digital (A/D) and Digital-to-Analog (D/A) Conversion
- Signal Gating


## description/ordering information

The CD4051B, CD4052B, and CD4053B analog multiplexers are digitally-controlled analog switches that have low ON impedance and very low OFF leakage current. Control of analog signals up to $20 \mathrm{~V}_{\text {P-p }}$ can be achieved by digital signal amplitudes of 4.5 V to 20 V (If $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}}=3 \mathrm{~V}$, a $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}$ of up to 13 V can be controlled; for $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{E E}$ level differences above 13 V , a $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}}$ of at least 4.5 V is required). For example, if $\mathrm{V}_{\mathrm{DD}}=4.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}$, and $\mathrm{V}_{\mathrm{EE}}=-13.5 \mathrm{~V}$, analog signals from -13.5 V to 4.5 V can be controlled by digital inputs of 0 V to 5 V . These multiplexer circuits dissipate extremely low quiescent power over the full $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}}$ and $\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}$ supply-voltage ranges, independent of the logic state of the control signals. When a logic high $(\mathrm{H})$ is present at the inhibit (INH) input, all channels are off.

ORDERING INFORMATION $\dagger$

| $\mathrm{T}_{\mathrm{A}}$ | PACKAGE ${ }^{\dagger}$ |  | ORDERABLE <br> PART NUMBER | TOP-SIDE MARKING |
| :---: | :---: | :---: | :---: | :---: |
| $-40^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ | SOIC - M | Reel of 2500 | CD4051BQM96Q1 | CD4051Q |
|  | TSSOP - PW | Reel of 2000 | CD4051BQPWRQ1 | CM051BQ |
|  | SOIC - M | Reel of 2500 | CD4052BQM96Q1§ | CD4052Q |
|  | TSSOP - PW | Reel of 2000 | CD4052BQPWRQ1§ | CD4052Q |
|  | SOIC - M | Reel of 2500 | CD4053BQM96Q1 | CD4053Q |
|  | TSSOP - PW | Reel of 2000 | CD4053BQPWRQ1§ | CD4053Q |

${ }^{\dagger}$ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.
$\ddagger$ Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.
§ Product Preview

## CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS

WITH LOGIC-LEVEL CONVERSION
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## description/ordering information (continued)

The CD4051B is a single eight-channel multiplexer that has three binary control inputs ( $A, B$, and $C$ ) and an inhibit input. The three binary signals select one of eight channels to be turned on and connect one of the eight inputs to the output.
The CD4052B is a differential four-channel multiplexer that has two binary control inputs ( $A$ and $B$ ) and an inhibit input. The two binary input signals select one of four pairs of channels to be turned on and connect the analog inputs to the outputs.

The CD4053B is a triple two-channel multiplexer with three separate digital control inputs ( $\mathrm{A}, \mathrm{B}$, and C ) and an inhibit input. Each control input selects one of a pair of channels, which are connected in a single-pole, double-throw configuration.

When these devices are used as demultiplexers, the CHANNEL IN/OUT terminals are the outputs, and the common (COM OUT/IN) terminals are the inputs.
CD4051
M OR PW PACKAGE
(TOP VIEW)
CD4052
M OR PW PACKAGE
(TOP VIEW)

CD4053
M OR PW PACKAGE
(TOP VIEW)

| IN/OUT by [ | ${ }_{1} \cup_{16}$ | $\mathrm{V}_{\mathrm{DD}}$ |
| :---: | :---: | :---: |
| IN/OUT bx [ | 215 | OUT/IN bx or by |
| IN/OUT cy | 314 | OUT/IN ax or ay |
| N CX OR CY [ | 413 | ] IN/OUT ay |
| IN/OUT CX | 512 | IN/OUT ax |
| INH | 611 | ] A |
| $\mathrm{V}_{\mathrm{EE}}$ | 710 | B |
| $\mathrm{V}_{\text {SS }}$ | 89 | C |

Function Tables

| CD4051 |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| INPUTS |  |  |  | ON |
| INH | C | B | A | CHANNEL |
| L | L | L | L | 0 |
| L | L | L | H | 1 |
| L | L | H | L | 2 |
| L | L | H | H | 3 |
| L | H | L | L | 4 |
| L | H | L | H | 5 |
| L | H | H | L | 6 |
| L | H | H | H | 7 |
| H | X | X | X | None |


| CD4052 |  |  |  |
| :---: | :---: | :---: | :---: |
| INPUTS | ON |  |  |
| INH | B | A | CHANNEL |
| L | L | L | $0 x, 0 y$ |
| L | L | H | $1 \mathrm{x}, 2 \mathrm{y}$ |
| L | H | L | $2 x, 2 y$ |
| L | H | H | $3 x, 3 y$ |
| H | X | X | None |

X= don't care

| CD4053 |  |  |
| :--- | :---: | :---: |
| INPUTS ON  <br> INH A OR B OR C CHANNEL <br> L L ax or bx or cx <br> L H ay or by or cy <br> H X None <br> $X=$ don't care   |  |  |

## CD4051B-Q1, CD4052B-Q1, CD4053B-Q1

## CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS

WITH LOGIC-LEVEL CONVERSION
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logic diagram (positive logic)

$\dagger$ All inputs are protected by CMOS protection network.

$\dagger$ All inputs are protected by CMOS protection network.

# CD4051B-Q1, CD4052B-Q1, CD4053B-Q1 CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS WITH LOGIC-LEVEL CONVERSION 

## logic diagrams (positive logic) (continued)

## CD4053B


absolute maximum ratings over operating free-air temperature (unless otherwise noted) ${ }^{\ddagger}$
Supply voltage range, $\mathrm{V}+$ to V - (voltages referenced to $\mathrm{V}_{\text {SS }}$ terminal) .......................... -0.5 to 20 V
DC input voltage range .................................................................... 0.5 V to $\mathrm{V}_{\mathrm{DD}}+0.5 \mathrm{~V}$
DC input current, any one input ....................................................................... $\pm 10 \mathrm{~mA}$
Package thermal impedance, $\theta_{\mathrm{JA}}$ (see Note 1): M package ......................................... 73² $\mathrm{C} / \mathrm{W}$
PW package ........................................ $108^{\circ} \mathrm{C} / \mathrm{W}$

Lead temperature (during soldering):



[^0]
## CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS

recommended operating conditions

|  |  | MIN | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{DD}}$ | Supply voltage | 5 | 20 | V |
|  | Operating free-air temperature | -40 | 125 | ${ }^{\circ} \mathrm{C}$ |

electrical characteristics, $\mathrm{V}_{\text {SUPPLY }}= \pm 5 \mathrm{~V}, \mathrm{~A}_{\mathrm{V}}=1 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=100 \Omega$, unless otherwise noted (see Note 2)

| PARAMETER |  | TEST CONDITIONS |  | $V_{D D}$ <br> (V) | LIMITS AT INDICATED TEMPERATURES |  |  |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $-40^{\circ} \mathrm{C}$ | $125^{\circ} \mathrm{C}$ |  | $25^{\circ} \mathrm{C}$ |  |  |  |
|  |  | MIN |  |  | TYP | MAX |  |
| $\mathrm{I}_{\mathrm{DD}}$ | Quiescent device current |  |  |  | 5 | 5 | 150 |  | 0.04 | 5 | $\mu \mathrm{A}$ |
|  |  |  |  | 10 | 10 | 300 |  | 0.04 | 10 |  |  |
|  |  |  |  | 15 | 20 | 600 |  | 0.04 | 20 |  |  |
|  |  |  |  | 20 | 100 | 3000 |  | 0.08 | 100 |  |  |
| Signal Input ( $\mathrm{V}_{\text {is }}$ ) and Output ( $\mathrm{V}_{\text {os }}$ ) |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{r}_{\text {on }}$ | Drain-to-source ON-state resistance | $\begin{aligned} & \mathrm{V}_{\mathrm{EE}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \\ & \mathrm{~V}_{\mathrm{IS}}=0 \text { to } \mathrm{V}_{\mathrm{DD}} \end{aligned}$ |  | 5 | 850 | 1300 |  | 470 | 1050 | $\Omega$ |  |
|  |  |  |  | 10 | 330 | 550 |  | 180 | 400 |  |  |
|  |  |  |  | 15 | 210 | 320 |  | 125 | 240 |  |  |
| $\Delta r_{\text {on }}$ | ON-state resistance difference between any two switches | $\mathrm{V}_{\mathrm{EE}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}$ |  | 5 |  |  |  | 15 |  | $\Omega$ |  |
|  |  |  |  | 10 |  |  |  | 10 |  |  |  |
|  |  |  |  | 15 |  |  |  | 5 |  |  |  |
|  | Input/output leakage current (switch off) | Any channel OFF (MAX) OFF (COM OUT/IN) (M $\mathrm{V}_{\mathrm{EE}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}$, S | or all channels <br> Note 3 | 18 | $\pm 0.1$ | $\pm 1$ |  | $\pm 10^{-5}$ | $\pm 0.1$ | $\mu \mathrm{A}$ |  |
| $\mathrm{C}_{\text {is }}$ | Input capacitance | $\mathrm{V}_{\mathrm{EE}}=-5 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-5 \mathrm{~V}$ |  | 5 |  |  |  | 5 |  | pF |  |
| $\mathrm{C}_{\text {os }}$ | Output capacitance | $\mathrm{V}_{\mathrm{EE}}=-5 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-5 \mathrm{~V}$ | CD4051 | 5 |  |  |  | 30 |  | pF |  |
|  |  |  | CD4052 |  |  |  |  | 18 |  |  |  |
|  |  |  | CD4053 |  |  |  |  | 9 |  |  |  |
| $\mathrm{C}_{\text {ios }}$ | Feedthrough capacitance | $\mathrm{V}_{\mathrm{EE}}=-5 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=-5 \mathrm{~V}$ |  | 5 |  |  | 0.2 |  |  | pF |  |
| $\mathrm{t}_{\mathrm{pd}}$ | Propagation delay (signal input to output) | $\begin{aligned} & V_{I S(p-p)}=V_{D D}, R_{L}=200 \mathrm{k} \Omega, \\ & C_{L}=50 \mathrm{pF}, \mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}}=20 \mathrm{~ns} \end{aligned}$ |  | 5 |  |  |  | 30 | 60 | ns |  |
|  |  |  |  | 10 |  |  |  | 15 | 30 |  |  |
|  |  |  |  | 15 |  |  |  | 10 | 20 |  |  |

NOTES: 2. Peak-to-peak voltage symmetrical about $\frac{\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}}{2}$
3. Determined by minimum feasible leakage measurement for automatic testing
electrical characteristics, $\mathrm{V}_{\text {SUPPLY }}= \pm 5 \mathrm{~V}, \mathrm{~A}_{\mathrm{V}}=1 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=100 \Omega$, unless otherwise noted (see Note 2) (continued)

| PARAMETER |  | TEST CONDITIONS | $\begin{aligned} & \mathrm{V}_{\mathrm{EE}} \\ & \text { (V) } \end{aligned}$ | $\begin{aligned} & V_{D D} \\ & (V) \end{aligned}$ | LIMITS AT INDICATED TEMPERATURES |  |  |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $-40^{\circ} \mathrm{C}$ |  |  | $125^{\circ} \mathrm{C}$ | $25^{\circ} \mathrm{C}$ |  |  |  |
|  |  | MIN |  |  |  | TYP | MAX |  |
| Control (Address or Inhibit), $\mathrm{V}_{\mathrm{C}}$ |  |  |  |  |  |  |  |  |  |  |
| VIL | Input low voltage |  | $\mathrm{V}_{\mathrm{IL}}=\mathrm{V}_{\mathrm{DD}}$ through $1 \mathrm{k} \Omega$, <br> $\mathrm{V}_{\mathrm{IH}}=\mathrm{V}_{\mathrm{DD}}$ through $1 \mathrm{k} \Omega$, <br> $R_{L}=1 \mathrm{k} \Omega$ to $V_{S S}$, <br> $\mathrm{I}_{\text {is }}<2 \mu \mathrm{~A}$ on all OFF channels | $\mathrm{V}_{\text {SS }}$ | 5 | 1.5 | 1.5 |  |  | 1.5 | V |
|  |  | $\mathrm{V}_{S S}$ |  | 10 | 3 | 3 |  |  | 3 |  |  |
|  |  | $\mathrm{V}_{S S}$ |  | 15 | 4 | 4 |  |  | 4 |  |  |
| $\mathrm{V}_{\mathrm{IH}}$ | Input high voltage | $\begin{aligned} & \mathrm{V}_{\mathrm{IL}}=\mathrm{V}_{\mathrm{DD}} \text { through } 1 \mathrm{k} \Omega, \\ & \mathrm{~V}_{\mathrm{IH}}=\mathrm{V}_{\mathrm{DD}} \text { through } 1 \mathrm{k} \Omega, \\ & \mathrm{R}_{\mathrm{L}}=1 \mathrm{k} \Omega \text { to } \mathrm{V}_{\mathrm{SS}}, \\ & \mathrm{I}_{\text {is }}<2 \mu \mathrm{~A} \text { on all OFF channels } \\ & \hline \end{aligned}$ | $\mathrm{V}_{S S}$ | 5 | 3.5 | 3.5 | 3.5 |  |  | V |  |
|  |  |  | $\mathrm{V}_{S S}$ | 10 | 7 | 7 | 7 |  |  |  |  |
|  |  |  | $\mathrm{V}_{\text {SS }}$ | 15 | 11 | 11 | 11 |  |  |  |  |
| IIN | Input current | $\mathrm{V}_{\mathrm{IN}}=0 \mathrm{~V}, 18 \mathrm{~V}$ |  | 18 | $\pm 0.1$ | $\pm 1$ |  | $\pm 10^{-5}$ | $\pm 0.1$ | $\mu \mathrm{A}$ |  |
| $\mathrm{t}_{\mathrm{pd} 1}$ | Address-to-signal OUT (channels ON or OFF) propagation delay | $\begin{aligned} & \mathrm{t}_{\mathrm{r}} \mathrm{t}_{\mathrm{f}}=20 \mathrm{~ns}, \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \\ & \mathrm{R}_{\mathrm{L}}=10 \mathrm{k} \Omega, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \end{aligned}$ <br> See Figure 10, Figure 11, and Figure 14 | 0 | 5 |  |  |  | 450 | 720 | ns |  |
|  |  |  | 0 | 10 |  |  |  | 160 | 320 |  |  |
|  |  |  | 0 | 15 |  |  |  | 120 | 240 |  |  |
|  |  |  | -5 | 5 |  |  |  | 225 | 450 |  |  |
| $\mathrm{t}_{\mathrm{pd} 2}$ | Inhibit-to-signal OUT (channel turning ON) propagation delay | $\begin{aligned} & \mathrm{t}_{\mathrm{r}} \mathrm{t}_{\mathrm{f}}=20 \mathrm{~ns}, \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \\ & \mathrm{R}_{\mathrm{L}}=1 \mathrm{k} \Omega, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \end{aligned}$$\text { See Figure } 11$ | 0 | 5 |  |  |  | 400 | 720 | ns |  |
|  |  |  | 0 | 10 |  |  |  | 160 | 320 |  |  |
|  |  |  | 0 | 15 |  |  |  | 120 | 240 |  |  |
|  |  |  | -10 | 5 |  |  |  | 200 | 400 |  |  |
| $t_{\text {pd3 }}$ | Inhibit-to-signal OUT (channel turning OFF) propagation delay | $\begin{aligned} & \mathrm{t}_{\mathrm{r},} \mathrm{t}_{\mathrm{f}}=20 \mathrm{~ns}, \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \\ & \mathrm{R}_{\mathrm{L}}=10 \mathrm{k} \Omega, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \end{aligned}$$\text { See Figure } 15$ | 0 | 5 |  |  |  | 200 | 450 | ns |  |
|  |  |  | 0 | 10 |  |  |  | 90 | 210 |  |  |
|  |  |  | 0 | 15 |  |  |  | 70 | 160 |  |  |
|  |  |  | -10 | 5 |  |  |  | 130 | 300 |  |  |
| $\mathrm{C}_{\text {IN }}$ | Input capacitance, any address or inhibit input |  |  |  |  |  |  | 5 | 7.5 | pF |  |

NOTES: 2: Peak-to-peak voltage symmetrical about $\frac{\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}}{2}$
3: Determined by minimum feasible leakage measurement for automatic testing

## CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS

## electrical specifications

| PARAMETER |  | TEST CONDITIONS |  | $\begin{aligned} & V_{\text {IS }} \\ & (\mathrm{V}) \end{aligned}$ | $V_{D D}$ <br> (V) | LIMITS ATINDICATEDTEMPERATURES |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  |
|  |  | MIN | TYP |  |  | MAX |  |
| -3-dB cutoff frequency, channel ON (sine-wave input) |  |  |  | $\mathrm{R}_{\mathrm{L}}=1 \mathrm{k} \Omega,$ <br> $\mathrm{V}_{\text {OS }}$ at COM OUT/IN, See Note 2, $V_{\text {Os }}$ at COM OUT/IN | CD4053 | 5 | 10 |  | 30 |  | MHz |
|  |  | CD4052 | 5 |  | 10 |  | 25 |  |  |  |
|  |  | CD4051 | 5 |  | 10 |  | 20 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}, 20 \log \mathrm{~V}_{\mathrm{OS}} / \mathrm{V}_{\mathrm{IS}}=-3 \mathrm{~dB},$ <br> $V_{\text {OS }}$ at any channel |  |  |  |  | 60 |  |  |  |
| THD | Total harmonic distortion | $\mathrm{R}_{\mathrm{L}}=10 \mathrm{k} \Omega,$ <br> See Note 2 |  | 2 | 5 |  | 0.3 |  | \% |  |
|  |  |  |  | 3 | 10 |  | 0.2 |  |  |  |
|  |  |  |  | 5 | 15 |  | 0.12 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\text {SS }}, \mathrm{f}_{\text {is }}=1-\mathrm{kHz}$ sine wave |  |  |  |  | 0.12 |  |  |  |
|  | $-40-\mathrm{dB}$ feedthrough frequency (all channels OFF) | $R_{\mathrm{L}}=1 \mathrm{k} \Omega,$ <br> $\mathrm{V}_{\text {OS }}$ at COM OUT/IN, <br> See Note 2 | CD4053 | 5 | 10 |  | 8 |  | MHz |  |
|  |  |  | CD4052 | 5 | 10 |  | 10 |  |  |  |
|  |  |  | CD4051 | 5 | 10 |  | 12 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}, 20 \log \mathrm{~V}_{\mathrm{OS}} / \mathrm{V}_{\mathrm{IS}}=-40 \mathrm{~dB},$ <br> $\mathrm{V}_{\text {OS }}$ at any channel |  |  |  |  | 8 |  |  |  |
|  | $-40-\mathrm{dB}$ signal crosstalk frequency | $\mathrm{R}_{\mathrm{L}}=1 \mathrm{k} \Omega$, between any two channels, See Note 2 |  | 5 | 10 |  | 3 |  | MHz |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}, 20 \log \mathrm{~V}_{\mathrm{OS}}$ Between sections, Me | CD4052 |  |  |  | 6 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}, 20 \log \mathrm{~V}_{\mathrm{OS}}$ <br> Between sections, Measured on any chan |  |  |  |  | 10 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}, 20 \log \mathrm{~V}_{\mathrm{OS}}$ <br> Between any two sect In pin 2, Out pin 14 | CD4053 |  |  |  | 2.5 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{EE}}=\mathrm{V}_{\mathrm{SS}}$, 2010g $\mathrm{V}_{\mathrm{OS}}$ Between any two sect In pin 15, Out pin 14 |  |  |  |  | 6 |  |  |  |
|  | Address or inhibit to signal crosstalk | $\mathrm{R}_{\mathrm{L}}=10 \mathrm{k} \Omega$, See Note 4 |  |  | 10 |  | 65 |  | mV $\mathrm{P}_{\text {PEAK }}$ |  |
|  |  | $\begin{aligned} & V_{E E}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}}=20 \mathrm{~ns}, \\ & \mathrm{~V}_{\mathrm{CC}}=\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{SS}} \text { (square wave) } \end{aligned}$ |  |  |  |  | 65 |  |  |  |

NOTES: 2. Peak-to-peak voltage symmetrical about $\frac{\mathrm{V}_{\mathrm{DD}}-\mathrm{V}_{\mathrm{EE}}}{2}$
4. Both ends of channel

# CD4051B-Q1, CD4052B-Q1, CD4053B-Q1 CMOS ANALOG MULTIPLEXERS/DEMULTIPLEXERS WITH LOGIC-LEVEL CONVERSION 

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## TYPICAL CHARACTERISTICS



Figure 1


Figure 3

Figure 2

CHANNEL ON-STATE RESISTANCE
vs
INPUT SIGNAL VOLTAGE


Figure 4

## TYPICAL CHARACTERISTICS



Figure 5


Figure 7

DYNAMIC POWER DISSIPATION
vs SWITCHING FREQUENCY (CD4051B)


Figure 6

DYNAMIC POWER DISSIPATION
vs
SWITCHING FREQUENCY (CD4053B)


Figure 8

## PARAMETER MEASUREMENT INFORMATION



NOTE: The $A, B, C$, and INH input logic levels are $L=V_{S S}$ and $H=V_{D D}$. The analog signal (through the $T G$ ) may swing from $V_{E E}$ to $V_{D D}$.
Figure 9. Typical Bias-Voltage Test Circuits


Figure 10. Channel Turned ON Waveforms

$$
\left(R_{L}=1 \mathrm{k} \Omega\right)
$$



Figure 11. Channel Turned OFF Waveforms ( $R_{L}=1 \mathrm{k} \Omega$ )


Figure 12. OFF Channel Leakage Current, Any Channel OFF


Figure 13. OFF Channel Leakage Current, All Channels OFF


Figure 14. Propagation Delay, Address Input to Signal Output


Figure 15. Propagation Delay, Inhibit Input to Signal Output

## PARAMETER MEASUREMENT INFORMATION



Measure <2 $\mu \mathrm{A}$ on All OFF Channels (e.g., Channel 6)


Measure $<2 \mu \mathrm{~A}$ on All OFF Channels (e.g., Channel 2x)


Measure $<2 \mu \mathrm{~A}$ on All OFF Channels (e.g., Channel by)

Figure 16. Input-Voltage Test Circuit (Noise Immunity)


Figure 17. Quiescent Device Current


Figure 18. Channel ON-Resistance Test Circuit

PARAMETER MEASUREMENT INFORMATION


NOTE: Measure inputs sequentially to both $\mathrm{V}_{\mathrm{DD}}$ and $\mathrm{V}_{\mathrm{SS}}$. Connect all unused inputs to either $\mathrm{V}_{\mathrm{DD}}$ or $\mathrm{V}_{\mathrm{SS}}$.


NOTE: Measure inputs sequentially to both $\mathrm{V}_{\mathrm{DD}}$ and $\mathrm{V}_{\mathrm{SS}}$. Connect all unused inputs to either $\mathrm{V}_{\mathrm{DD}}$ or $\mathrm{V}_{\mathrm{SS}}$.

Figure 19. Input Current


Figure 20. Feedthrough
Figure 21. Crosstalk Between Any Two Channels


Figure 22. Crosstalk Between Duals or Triplets (CD4052B, CD4053B)


Figure 23. Typical Time-Division Application of the CD4052B

## APPLICATION INFORMATION

In applications where separate power sources drive $\mathrm{V}_{\mathrm{DD}}$ and the signal inputs, the $\mathrm{V}_{\mathrm{DD}}$ current capability should exceed $V_{D D} / R_{L}$ ( $R_{L}=$ effective external load). This provision avoids permanent current flow or clamp action on the $V_{D D}$ supply when power is applied or removed from the CD4051B, CD4052B, or CD4053B.


Figure 24. 24-to-1 Multiplexer Addressing

INSTRUMENTS
PACKAGE OPTION ADDENDUM
www.ti.com

## PACKAGING INFORMATION

| Orderable Device | Status <br> (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan <br> (2) | Lead/Ball Finish | MSL Peak Temp <br> (3) | Op Temp ( ${ }^{\circ} \mathrm{C}$ ) | Top-Side Markings <br> (4) | Samples |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CD4051BQPWRG4Q1 | ACTIVE | TSSOP | PW | 16 | 2000 | Green (RoHS \& no $\mathrm{Sb} / \mathrm{Br}$ ) | CU NIPDAU | Level-1-260C-UNLIM | -40 to 125 | CM051BQ | Samples |
| CD4051BQPWRQ1 | ACTIVE | TSSOP | PW | 16 | 2000 | Green (RoHS \& no $\mathrm{Sb} / \mathrm{Br}$ ) | CU NIPDAU | Level-1-260C-UNLIM | -40 to 125 | CM051BQ | Samples |
| CD4053BQM96G4Q1 | ACTIVE | SOIC | D | 16 | 2500 | $\begin{aligned} & \text { Green (RoHS } \\ & \& \text { no } \mathrm{Sb} / \mathrm{Br} \text { ) } \end{aligned}$ | CU NIPDAU | Level-1-260C-UNLIM | -40 to 125 | CD4053Q | Samples |
| CD4053BQM96Q1 | ACTIVE | SOIC | D | 16 | 2500 | $\begin{aligned} & \text { Green (RoHS } \\ & \& \text { no } \mathrm{Sb} / \mathrm{Br} \text { ) } \end{aligned}$ | CU NIPDAU | Level-1-260C-UNLIM | -40 to 125 | CD4053Q | Samples |

${ }^{(1)}$ The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.
${ }^{(2)}$ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS \& no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb -Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed $0.1 \%$ by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb -Free products are suitable for use in specified lead-free processes
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb -Free (RoHS compatible) as defined above.
Green (RoHS \& no Sb/Br): Tl defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed $0.1 \%$ by weight in homogeneous material)
${ }^{(3)}$ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
${ }^{(4)}$ Only one of markings shown within the brackets will appear on the physical device.

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OTHER QUALIFIED VERSIONS OF CD4051B-Q1, CD4053B-Q1 :

- Catalog: CD4051B, CD4053B
- Military: CD4051B-MIL, CD4053B-MIL

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications


## TAPE AND REEL INFORMATION


*All dimensions are nominal

| Device | Package <br> Type | Package <br> Drawing | Pins | SPQ | Reel <br> Diameter <br> $(\mathbf{m m})$ | Reel <br> Width <br> W1 $(\mathbf{m m})$ | A0 <br> $(\mathbf{m m})$ | B0 <br> $(\mathbf{m m})$ | K0 <br> $(\mathbf{m m})$ | P1 <br> $(\mathbf{m m})$ | W <br> $(\mathbf{m m})$ | Pin1 <br> Quadrant |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CD4051BQPWRG4Q1 | TSSOP | PW | 16 | 2000 | 330.0 | 12.4 | 6.9 | 5.6 | 1.6 | 8.0 | 12.0 | Q1 |
| CD4051BQPWRQ1 | TSSOP | PW | 16 | 2000 | 330.0 | 12.4 | 6.9 | 5.6 | 1.6 | 8.0 | 12.0 | Q1 |


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CD4051BQPWRG4Q1 | TSSOP | PW | 16 | 2000 | 367.0 | 367.0 | 35.0 |
| CD4051BQPWRQ1 | TSSOP | PW | 16 | 2000 | 367.0 | 367.0 | 35.0 |

D (R-PDSO-G16)


NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.

C Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed $0.006(0,15)$ each side.
D Body width does not include interlead flash. Interlead flash shall not exceed $0.017(0,43)$ each side.
E. Reference JEDEC MS-012 variation AC.

D (R-PDSO-G16)


NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC-7351 is recommended for alternate designs.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

PW (R-PDSO-G16)


NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
D Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
E. Falls within JEDEC MO-153

## PW (R-PDSO-G16)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC-7351 is recommended for alternate designs.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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[^0]:    $\ddagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
    NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

